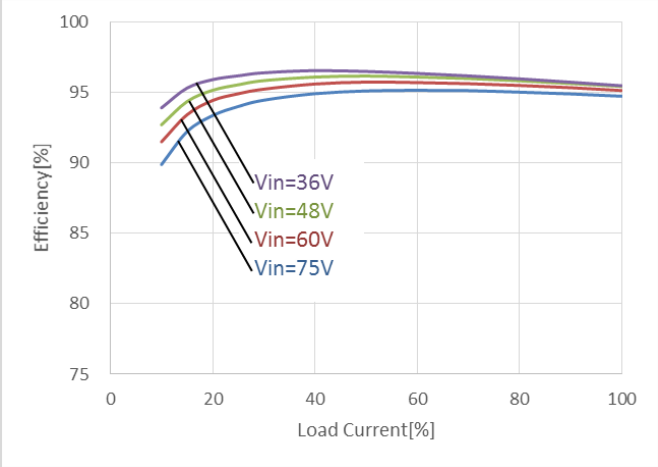
Reliability test Specifications

Reliability Test	
High temperature load test	Expose 100hrs in +65℃±3℃ with 48Vin.
High temperature high humidity load test	Expose 100hrs in +65℃±3℃/90%RH with 10A load and 48Vin.
ESD test	Expose condition A(r=1500Ω, C=100pF) on EIAJ ED-4701 method C-111.
Temperature cycling test	Expose 100 cycles in the following sequence..-40℃±3℃/30min->, Room temperature(+25℃)/10sec->+85℃±3℃/30min->Room temperature(+25℃)/10sec.

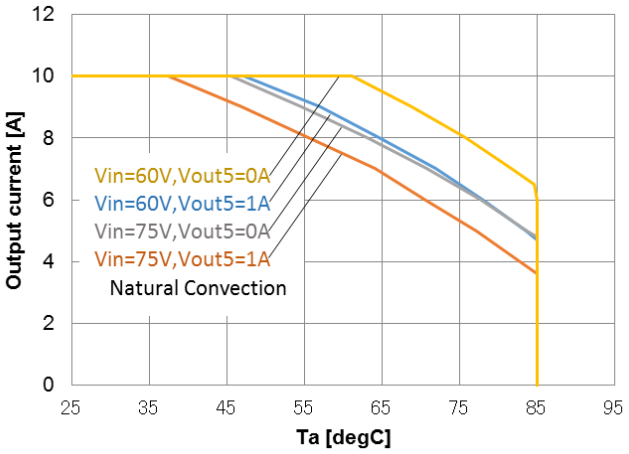
After above test, hold in the room temperature(+25℃) for 24hrs, then measure above parameters indicated (**) in the above specification.

Typical Performance Data

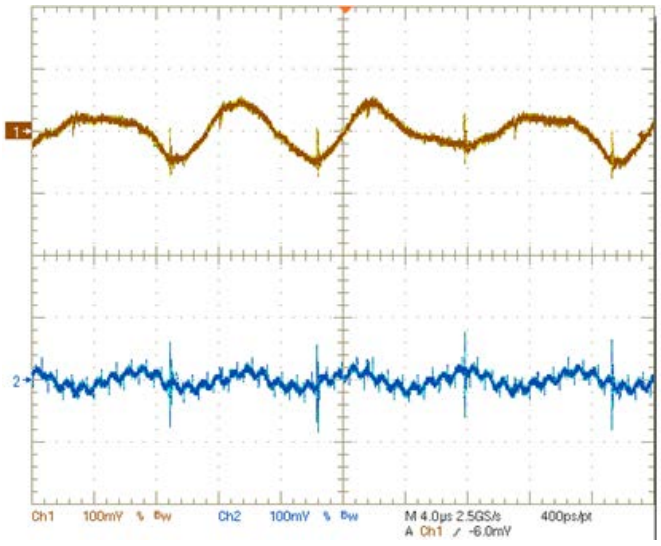
Effeciency vs, Line Voltage and Load Current @Ta = +25℃
(100% : Vout12=10A,Vout5=1A)



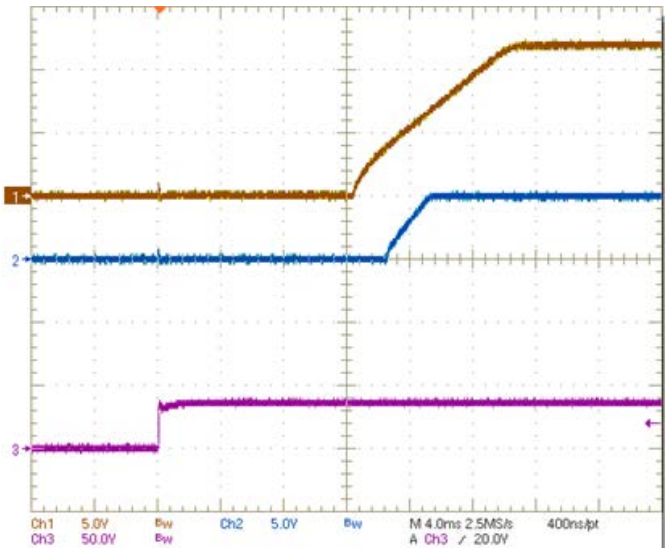
Maximum Current Temperature Derating at Sea Level (Vin=60V)
(100% : Vout12=10A,Vout5=1A)



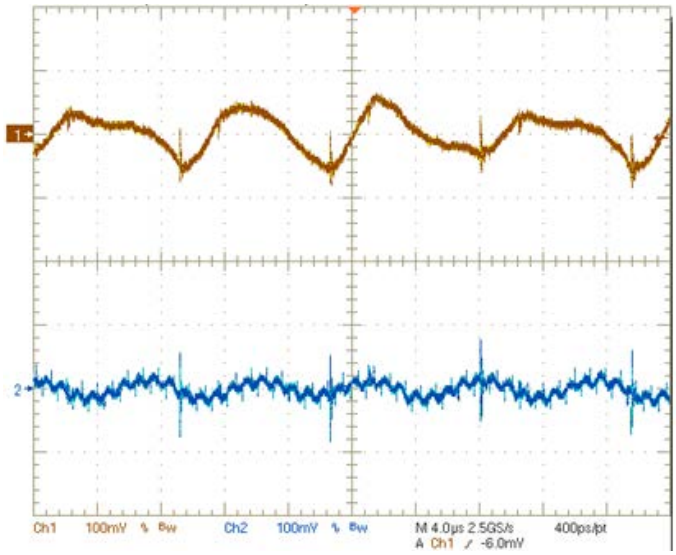
Output Ripple and Noise (Vin = 36V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF, Scope Bandwidth = 20MHz) Trace 1 = Vout main,Trace 2 = Vout aux



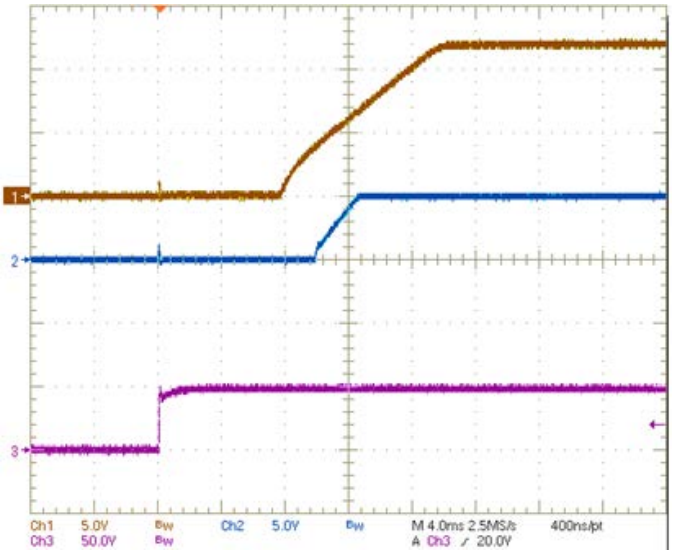
Turn On Delay (Vin = 36V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF)
Trace1 = Vout main, Trace 2 = Vout aux, Trace 3 = Vin



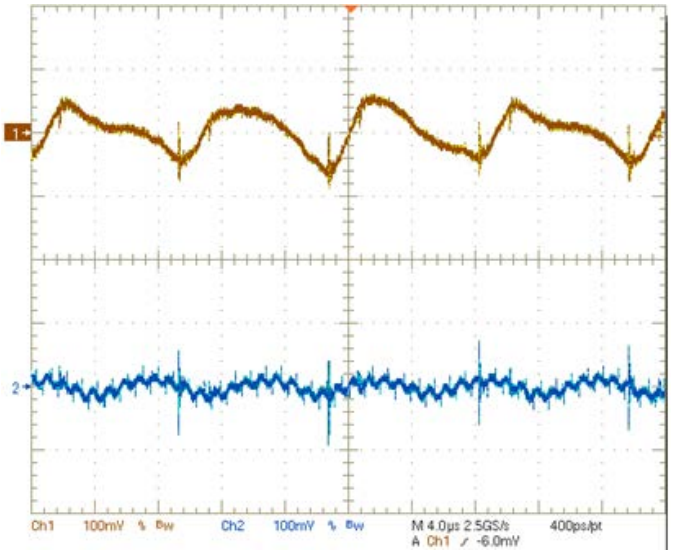
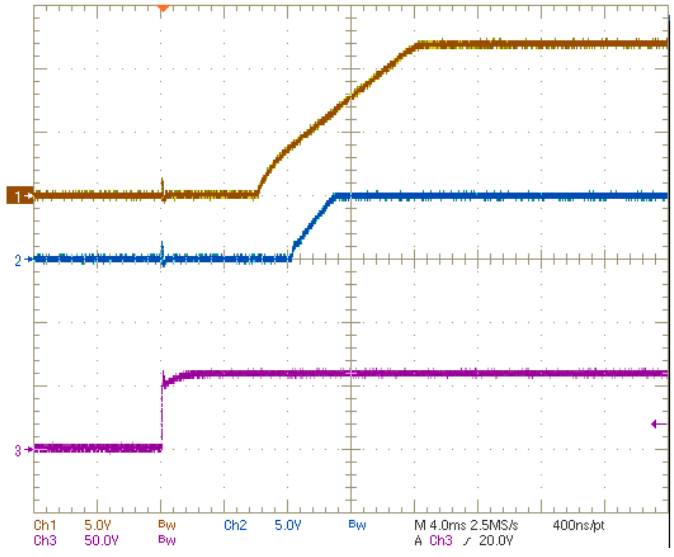
Output Ripple and Noise (Vin = 48V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF, Scope Bandwidth = 20MHz) Trace 1 = Vout main,Trace 2 = Vout aux



Turn On Delay (Vin = 48V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF)
Trace1 = Vout main, Trace 2 = Vout aux, Trace 3 = Vin



Output Ripple and Noise (Vin = 60V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF, Scope Bandwidth = 20MHz) Trace 1 = Vout main,Trace 2 = Vout aux



Turn On Delay (Vin = 60V, Iout main = 8A, Iout aux = 1A, Cload = 0.1uF)
Trace1 = Vout main, Trace 2 = Vout aux, Trace 3 = Vin